



Specification of Automotive MLCC

- Supplier : Samsung electro-mechanics
- Product : Multi-layer Ceramic Capacitor
- Samsung P/N :
- CL31B224KBP5PNE
- Description : CAP, 220nF, 50V, ±10%, X7R, 1206
- AEC-Q 200 Specified

A. Samsung Part Number

			<u>CL</u>	<u>31</u>	<u>B</u>	<u>224</u>	<u>K</u>	<u>B</u>	<u>P</u>	<u>5</u>	<u>P</u>	<u>N</u>	E					
			1	2	3	4	5	6	1	8	9	10	1					
1	Series	Samsun	ng Multi	-layer	Cera	mic Ca	pacit	or										
2	Size	1206	-	-				± 0.1	5	mm		W:		1.6 ± 0).15	mm		
3	Dielectric	X7R					(8)	Innei	r elec	trode			Ni C	Open ma	ode			
4	Capacitance	220	nF				J	Term						Ag-epox				
5	Capacitance	±10	%					Plati	ng				Sn 10	00%		(Pb	Free)	
	tolerance						9	Prod	uct				Autor	motive				
6	Rated Voltage	50	V				10	Grad	e co	de			Stand	dard				
\bigcirc	Thickness	1.15 :	± 0.15	mm			1	Pack	agin	g			Embo	ossed T	уре	, 7 " i	reel	

B. Reliablility Test and Judgement condition

	Performance	Test condition					
High Temperature	Appearance : No abnormal exterior appearance	Unpowered, 1000hrs@T=150℃					
Exposure	Capacitance Change : Within ±10%	Measurement at 24±2hrs after test conclusion					
	Tan δ: 0.03 max						
	IR : More than 10,000 Ω or 500 $\Omega \times \mu F$						
	Whichever is Smaller						
Temperature Cycling	Appearance : No abnormal exterior appearance	1000Cycles					
	Capacitance Change : Within ±10%	Measurement at 24±2hrs after test conclusion					
	Tan δ: 0.03 max	1 cycle condition :					
	IR : More than 10,000M Ω or 500M Ω × μ F	-55+0/-3℃(15±3min) -> Room Temp(1min.)					
	Whichever is Smaller	-> 125+3/-0℃(15±3min) -> Room Temp(1min.)					
Destructive Physical	No Defects or abnormalities	Per EIA 469					
Analysis							
Moisture Resistance	Appearance : No abnormal exterior appearance	10Cycles, t=24hrs/cycle					
	Capacitance Change : Within ±12.5%	Heat (25~65 $^\circ \!\!\!\!\!^\circ$) and humidity (80~98%), Unpowered					
	Tan δ: 0.03 max	measurement at 24±2hrs after test conclusion					
	IR : More than 10,000 $\mbox{M}\Omega$ or 500 $\mbox{M}\Omega \times \mu F$						
	Whichever is Smaller						
Humidity Bias	Appearance : No abnormal exterior appearance	1000hrs 85℃/85%RH, Rated Voltate and 1.3~1.5V,					
	Capacitance Change : Within ±12.5%	Add 100kohm resistor					
	Tan δ: 0.035 max	Measurement at 24±2hrs after test conclusion					
	IR : More than 500MΩ or 25 MΩ× μ F	The charge/discharge current is less than 50mA.					
	Whichever is Smaller						
High Temperature	Appearance : No abnormal exterior appearance	1000hrs @ TA=125°C, 200% Rated Voltage,					
Operating Life	Capacitance Change : Within ±12.5%	Measurement at 24±2hrs after test conclusion					
	Tan δ: 0.035 max	The charge/discharge current is less than 50mA.					
	IR : More than 1000№ or 50№×µF						
	Whichever is Smaller						

	Performance	Test condition						
External Visual	No abnormal exterior appearance	Microscope ('10)						
Physical Dimensions	Within the specified dimensions	Using The calipers						
Mechanical Shock	Appearance : No abnormal exterior appearance Capacitance Change : Within $\pm 10\%$ Tan δ , IR : initial spec.	Three shocks in each direction should be applied along 3 mutually perpendicular axes of the test specimen (18 shocks) Peakvalue Duration Wave Velocity 1,500G 0.5ms Half sine 4.7m/sec.						
Vibration	Appearance : No abnormal exterior appearance Capacitance Change : Within ±10% Tan δ, IR : initial spec.	5g's for 20min., 12cycles each of 3 orientations, Use 8"×5" PCB 0.031" Thick 7 secure points on one long side and 2 secure points at corners of opposite sides. Parts mounted within 2" from any secure point. Test from 10~2000Hz.						
Resistance to Solder Heat	Appearance : No abnormal exterior appearance Capacitance Change : Within ±10% Tan δ, IR : initial spec.	Solder pot : 260±5℃, 10±1sec.						
Thermal Shock	Appearance : No abnormal exterior appearance Capacitance Change : Within ±10% Tan δ, IR : initial spec.	 -55℃/+125℃. Note: Number of cycles required-300, Maximum transfer time-20 sec, Dwell time-15min. Air-Air 						
ESD	Appearance : No abnormal exterior appearance Capacitance Change : Within ±10% Tan δ, IR : initial spec.	AEC-Q200-002						
Solderability	95% of the terminations is to be soldered evenly and continuously	a) Preheat at 155°C for 4 hours, Immerse in solder for 5s at 245±5°C b) Steam aging for 8 hours, Immerse in solder for 5s at 245±5°C c) Steam aging for 8 hours, Immerse in solder for 120s at 260±5°C solder : a solution ethanol and rosin						
Electrical Characterization	Capacitance : Within specified tolerance Tan δ (DF) : 0.025 max. IR(25°C) : More than 10,000MΩ or 500MΩ×μF IR(125°C) : More than1,000MΩ or 10MΩ×μF Whichever is Smaller Dielectric Strength	The Capacitance /D.F. should be measured at 25°C, 1kt±10%, 1.0±0.2Vrms I.R. should be measured with a DC voltage not exceeding Rated Voltage @25°C, @125°C for 60~120 sec. Dielectric Strength : 250% of the rated voltage for 1~5 seconds						
Board Flex	Appearance : No abnormal exterior appearance Capacitance Change : Within ±10%	Bending to the limit (2mm) for 5 seconds						
Terminal Strength(SMD)	Appearance : No abnormal exterior appearance Capacitance Change : Within ±10%	18N, for 60±1 sec.						
Beam Load	Destruction value should not be exceed Chip Length ≥ 3.2mm a) Chip Thickness < 1.25mm : 15N b) Chip Thickness ≥ 1.25mm : 54.5N	Beam speed 2.5±0.25mm/sec						
Temperature Characterisitcs	X7R (From -55℃ to 125℃, Capacitance change sho	ud be within ±15%)						

C. Recommended Soldering method :

Reflow (Reflow Peak Temperature : 260+0/-5 $^\circ C$, 10sec. Max) Meet IPC/JEDEC J-STD-020 D Standard

* For the more detail Specification, Please refer to the Samsung MLCC catalogue.